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F-6971

**RESPONSE UNDER 37 CFR 1.116
EXPEDITED PROCEDURE
EXAMINING GROUP 2882**

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Seiichi HAYASHI, et al.
Serial No. : 09/852,111
Filed : May 9, 2001
For : METHOD AND APPARATUS FOR MEASURING
THIN FILM, AND THIN FILM DEPOSITION
SYSTEM
Group Art Unit : 2882
Examiner : Hoon K. Song

Certificate of Facsimile Transmission Under 37 CFR 1.8

I hereby certify that this correspondence is being transmitted in accordance with 37 CFR §1.6(d) to the United States Patent Office addressed to COMMISSIONER FOR PATENTS, P.O. Box 1450, Alexandria, VA 22313-1450 on December 30, 2004 to facsimile no. (703) 872-9306.

TOTAL NUMBER OF PAGES TRANSMITTED: 8

Herbert F. Ruschmann
(Name)


(Signature)

MAIL STOP 313(c)
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

**REQUEST FOR CONTINUED EXAMINATION
UNDER 37 CFR 1.114**

Sir:

A Request for Continued Examination (RCE) under 37 CFR 1.114 of the above-identified patent application is hereby made by the applicants. A petition 37

F6971 RCE form (PC 10).wpd

F-6971

Ser. No. 09/852,111

under CFR 1.313(c)(2) accompanies this request. Applicants provide the submission indicated below.

SUBMISSION UNDER 37 CFR 1.114

Submitted herewith is an IDC form PTO 1449 and a copy of a reference cited therein.

Please charge the fee of \$790 for the Request for Continued Examination to Deposit Account No. 10-1250.

F-6971

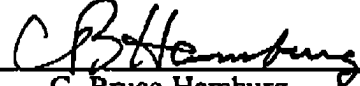
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Respectfully submitted,
Jordan and Hamburg LLP

By

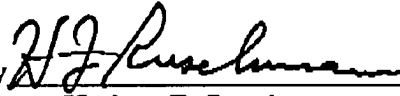

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